



# DIM1000NSM33-TS000

# **Single Switch IGBT Module**

DS6093-2 October 2013 (LN31017)

Replaces DS6093-1

### **FEATURES**

- 10µs Short Circuit Withstand
- High Thermal Cycling Capability
- High Current Density Enhanced DMOS SPT
- Isolated AISiC Base with AIN Substrates

#### **APPLICATIONS**

- High Reliability Inverters
- Motor Controllers
- Traction Drives
- Choppers

The Powerline range of high power modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 1200V to 6500V and currents up to 2400A.

The DIM1000NSM33-TS000 is a single switch 3300V, soft punch through n-channel enhancement mode, insulated gate bipolar transistor (IGBT) module. The IGBT has a wide reverse bias safe operating area (RBSOA) plus 10µs short circuit withstand. This device is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

### **ORDERING INFORMATION**

Order As:

### DIM1000NSM33-TS000

Note: When ordering, please use the complete part number

#### **KEY PARAMETERS**

$V_{CES}$		3300V
V <sub>CE(sat)</sub>	* (typ)	2.2V
l <sub>c</sub> ` ´	(max)	1000A
I <sub>C(PK)</sub>	(max)	2000A

<sup>\*</sup> Measured at the auxiliary terminals

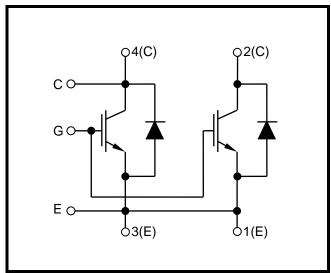


Fig. 1 Circuit configuration



Fig. 2 Package



### **ABSOLUTE MAXIMUM RATINGS**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25°C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
V <sub>CES</sub>	Collector-emitter voltage	V <sub>GE</sub> = 0V	3300	V
V <sub>GES</sub>	Gate-emitter voltage		±20	V
I <sub>C</sub>	Continuous collector current	T <sub>case</sub> = 110°C	1000	Α
I <sub>C(PK)</sub>	Peak collector current	1ms, T <sub>case</sub> = 140°C	2000	Α
P <sub>max</sub>	Max. transistor power dissipation	$T_{case} = 25^{\circ}C, T_{j} = 150^{\circ}C$	10.4	kW
l <sup>2</sup> t	Diode l <sup>2</sup> t value	$V_R = 0$ , $t_p = 10$ ms, $T_j = 125$ °C	320	kA <sup>2</sup> s
V <sub>isol</sub>	Isolation voltage – per module	Commoned terminals to base plate. AC RMS, 1 min, 50Hz	6000	V
$Q_{PD}$	Partial discharge – per module	IEC1287, V <sub>1</sub> = 3500V, V <sub>2</sub> = 2600V, 50Hz RMS	10	рС

### THERMAL AND MECHANICAL RATINGS

Internal insulation material:

Baseplate material:

Creepage distance:

Clearance:

CTI (Comparative Tracking Index):

AIN

AISiC

33mm

20mm

>600

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
R <sub>th(j-c)</sub>	Thermal resistance – transistor	Continuous dissipation – junction to case	-	-	12	°C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode	Continuous dissipation – junction to case	-	-	24	°C/kW
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink (per module)	Mounting torque 5Nm (with mounting grease)	-	-	8	°C/kW
_	Junction temperature	Transistor	-	-	150	°C
T <sub>j</sub>		Diode	-	-	150	°C
T <sub>stg</sub>	Storage temperature range	-	-40	-	125	°C
		Mounting – M6	-	-	5	Nm
	Screw torque	Electrical connections – M4	-	-	2	Nm
		Electrical connections – M8	-	-	10	Nm



# **ELECTRICAL CHARACTERISTICS**

 $T_{case}$  = 25°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
I <sub>CES</sub>	Collector cut-off current	$V_{GE} = 0V$ , $V_{CE} = V_{CES}$			4	mA
		$V_{GE} = 0V$ , $V_{CE} = V_{CES}$ , $T_{case} = 125$ °C			60	mA
		$V_{GE} = 0V$ , $V_{CE} = V_{CES}$ , $T_{case} = 150$ °C			100	mA
I <sub>GES</sub>	Gate leakage current	$V_{GE} = \pm 20V, V_{CE} = 0V$			1	μΑ
$V_{\text{GE(TH)}}$	Gate threshold voltage	$I_C = 80$ mA, $V_{GE} = V_{CE}$		5.7		V
		V <sub>GE</sub> = 15V, I <sub>C</sub> = 1000A		2.2		V
V <sub>CE(sat)</sub> †	Collector-emitter saturation voltage	$V_{GE} = 15V$ , $I_C = 1000A$ , $T_j = 125$ °C		2.8		V
	ŭ	$V_{GE} = 15V$ , $I_C = 1000A$ , $T_j = 150$ °C		3.0		V
I <sub>F</sub>	Diode forward current	DC		1000		Α
I <sub>FM</sub>	Diode maximum forward current	t <sub>p</sub> = 1ms		2000		Α
	Diode forward voltage (IGBT arm)	I <sub>F</sub> = 1000A		2.4		V
$V_F^{\dagger}$		$I_F = 1000A, T_j = 125^{\circ}C$		2.5		V
		$I_F = 1000A, T_j = 150$ °C		2.4		V
C <sub>ies</sub>	Input capacitance	$V_{CE} = 25V, V_{GE} = 0V, f = 1MHz$		170		nF
$Q_g$	Gate charge	±15V Including external C <sub>ge</sub>		17		μC
$C_{res}$	Reverse transfer capacitance	$V_{CE} = 25V, V_{GE} = 0V, f = 1MHz$		4		nF
L <sub>M</sub>	Module inductance			15		nΗ
R <sub>INT</sub>	Internal resistance			135		μΩ
SC <sub>Data</sub>	Short circuit current, I <sub>SC</sub>	$T_{j} = 150^{\circ}\text{C}, V_{CC} = 2500\text{V}$ $t_{p} \le 10\mu\text{s}, V_{GE} \le 15\text{V}$ $V_{CE  (max)} = V_{CES} - L^{*}  x  dl/dt$ $IEC  60747-9$		3700		А

# Note:

<sup>†</sup> Measured at the auxiliary terminals

L is the circuit inductance + L<sub>M</sub>



# **ELECTRICAL CHARACTERISTICS**

T<sub>case</sub> = 25°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1000A		1.9		μs
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		520		ns
E <sub>OFF</sub>	Turn-off energy loss	$V_{CE} = 1800V$		1800		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 2.2\Omega$ $R_{G(OFF)} = 2.2\Omega$		560		ns
t <sub>r</sub>	Rise time	$C_{qe} = 220 nF$		360		ns
E <sub>ON</sub>	Turn-on energy loss	L <sub>S</sub> ~ 100nH		1300		mJ
$Q_{rr}$	Diode reverse recovery charge	I <sub>F</sub> = 1000A		600		μC
I <sub>rr</sub>	Diode reverse recovery current	$V_{CE} = 1800V$		680		Α
E <sub>rec</sub>	Diode reverse recovery energy	$dI_F/dt = 2700A/\mu s$		750		mJ

# T<sub>case</sub> = 125°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1000A		2.0		μs
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		570		ns
E <sub>OFF</sub>	Turn-off energy loss	$V_{CE} = 1800V$		2000		mJ
$t_{d(on)}$	Turn-on delay time	$R_{G(ON)} = 2.2\Omega$ $R_{G(OFF)} = 2.2\Omega$		550		ns
t <sub>r</sub>	Rise time	$C_{qe} = 220nF$		420		ns
E <sub>ON</sub>	Turn-on energy loss	L <sub>S</sub> ~ 100nH		1600		mJ
$Q_{rr}$	Diode reverse recovery charge	I <sub>F</sub> = 1000A		935		μC
I <sub>rr</sub>	Diode reverse recovery current	V <sub>CE</sub> = 1800V		775		Α
E <sub>rec</sub>	Diode reverse recovery energy	$dI_F/dt = 2700A/\mu s$		1200		mJ

# T<sub>case</sub> = 150°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	$I_{\rm C} = 1000A$		2.0		μs
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		580		ns
E <sub>OFF</sub>	Turn-off energy loss	$V_{CE} = 1800V$		2100		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 2.2\Omega$ $R_{G(OFF)} = 2.2\Omega$		550		ns
t <sub>r</sub>	Rise time	$C_{qe} = 220 nF$		430		ns
E <sub>ON</sub>	Turn-on energy loss	L <sub>s</sub> ~ 100nH		1750		mJ
Q <sub>rr</sub>	Diode reverse recovery charge	I <sub>F</sub> = 1000A		1100		μC
I <sub>rr</sub>	Diode reverse recovery current	$V_{CE} = 1800V$		825		Α
E <sub>rec</sub>	Diode reverse recovery energy	$dI_F/dt = 2700A/\mu s$		1450		mJ



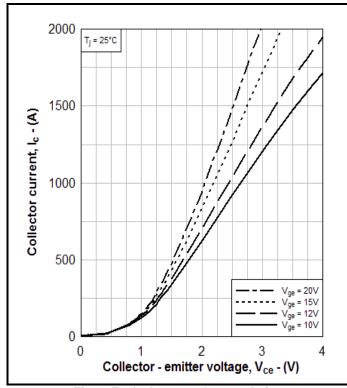


Fig. 3 Typical output characteristics

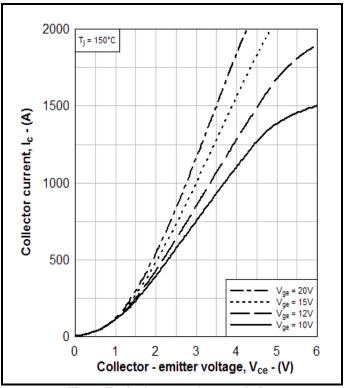


Fig. 4 Typical output characteristics

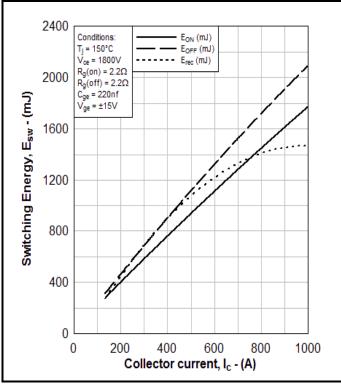


Fig. 5 Typical switching energy vs collector current

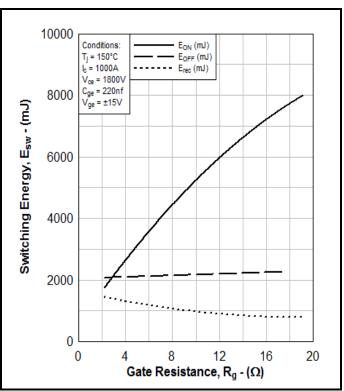


Fig. 6 Typical switching energy vs gate resistance



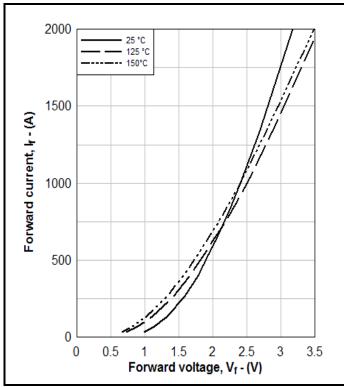


Fig. 7 Diode typical forward characteristics

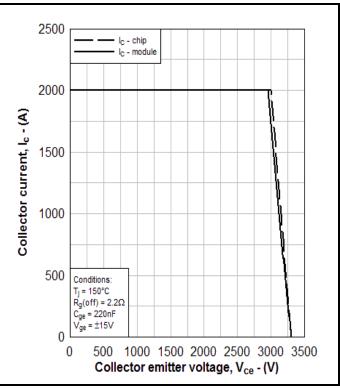


Fig. 8 Reverse bias safe operating area

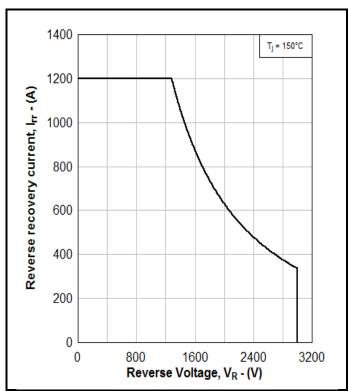


Fig. 9 Diode reverse bias safe operating area

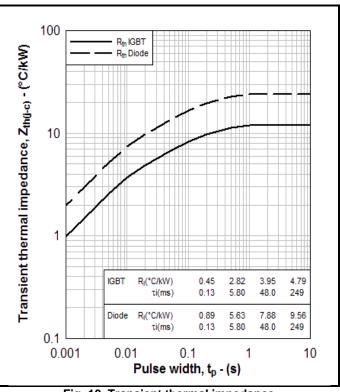


Fig. 10 Transient thermal impedance



### **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise.

### DO NOT SCALE.

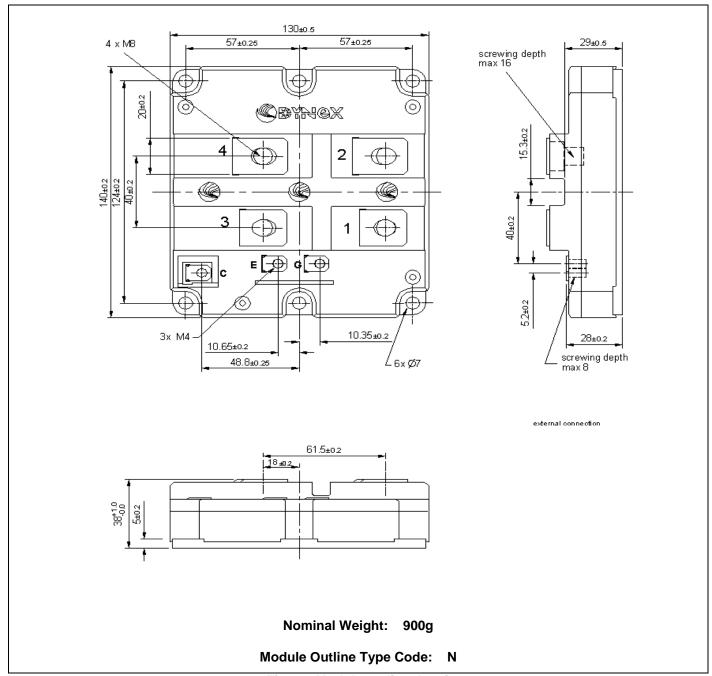


Fig. 11 Module outline drawing



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